

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/710,395 CHEN ET AL.	
		Examiner	Art Unit	Page 1 of 1 Yewebdar T. Tadesse

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,886,012	12-1989	Ikeno et al.	118/667
	B	US-6,193,783	02-2001	Sakamoto et al.	95/26
	C	US-6,903,030	06-2005	Ishii et al.	438/782
	D	US-5,778,911	07-1998	Yoshio, Akira	134/104.2
	E	US-5,058,805	10-1991	Anderson et al.	239/3
	F	US-5,733,375	03-1998	Fukuda et al.	118/666
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.